

HIGH SPEED 2K X 8 DUAL-PORT STATIC RAM WITH INTERRUPTS

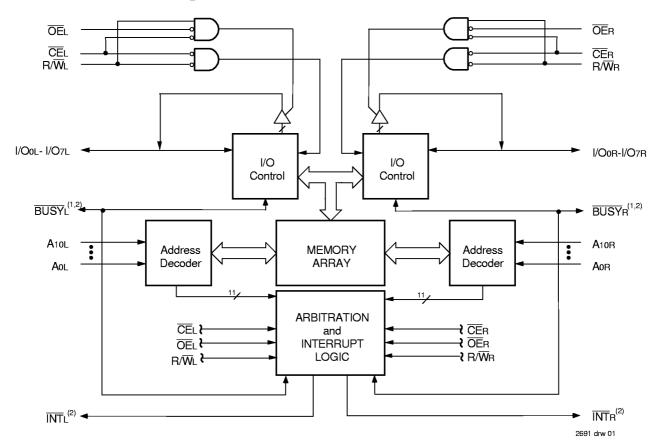
IDT71321SA/LA IDT71421SA/LA

Features

- High-speed access
 - Commercial: 20/25/35/55ns (max.)
 - Industrial: 55ns (max.)
- Low-power operation
 - IDT71321/IDT71421SAActive: 325mW (typ.)Standby: 5mW (typ.)
 - IDT71321/421LAActive: 325mW (typ.)Standby: 1mW (typ.)
- ◆ Two INT flags for port-to-port communications

- MASTER IDT71321 easily expands data bus width to 16-ormore-bits using SLAVE IDT71421
- On-chip port arbitration logic (IDT71321 only)
- BUSY output flag on IDT71321; BUSY input on IDT71421
- Fully asynchronous operation from either port
- Battery backup operation 2V data retention (LA only)
- TTL-compatible, single 5V ±10% power supply
- Available in 52-Pin PLCC, 64-Pin TQFP, and 64-Pin STQFP
- Industrial temperature range (-40°C to +85°C) is available for selected speeds

Functional Block Diagram



NOTES:

- IDT71321 (MASTER): BUSY is open drain output and requires pullup resistor of 270Ω.
 IDT71421 (SLAVE): BUSY is input.
- 2. Open drain output: requires pullup resistor of $270\Omega.$

MARCH 1999

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Description

The IDT71321/IDT71421 are high-speed 2K x 8 Dual-Port Static RAMs with internal interrupt logic for interprocessor communications. The IDT71321 is designed to be used as a stand-alone 8-bit Dual-Port Static RAM or as a "MASTER" Dual-Port Static RAM together with the IDT71421 "SLAVE" Dual-Port in 16-bit-or-more word width systems. Using the IDT MASTER/SLAVE Dual-Port Static RAM approach in 16-or-more-bit memory system applications results in full speed, error-free operation without the need for additional discrete logic.

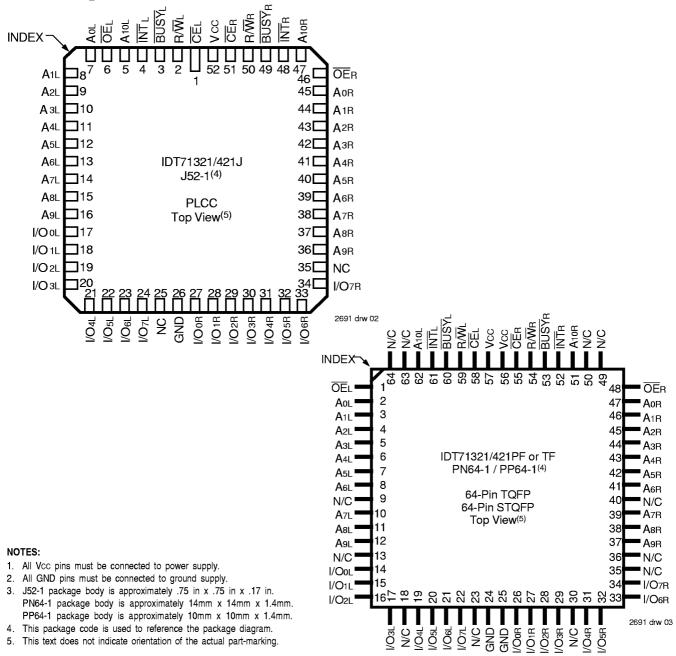
Both devices provide two independent ports with separate control,

address, and I/O pins that permit independent, asynchronous access for reads or writes to any location in memory. An automatic power down feature, controlled by $\overline{\text{CE}}$, permits the on chip circuitry of each port to enter a very low standby power mode.

Fabricated using IDT's CMOS high-performance technology, these devices typically operate on only 325mW of power. Low-power (LA) versions offer battery backup data retention capability, with each Dual-Port typically consuming 200µW from a 2V battery.

The IDT71321/IDT71421 devices are packaged in 52-pin PLCCs, 64-pin TQFPs, and 64-pin STQFPs.

Pin Configurations^(1,2,3)



Capacitance⁽¹⁾

(TA = +25°C, f = 1.0MHz) TQFP Only

Symbol	Parameter	Conditions ⁽²⁾	Max.	Unit
CIN	Input Capacitance	VIN = 3dV	9	pF
Соит	Output Capacitance	Vouτ = 3dV	10	pF

NOTES:

- This parameter is determined by device characterization but is not production tested.
- 2. 3dv references the interpolated capacitance when the input and output signals switch from 0V to 3V or from 3V to 0V.

Recommended Operating Temperature and Supply Voltage^(1,2)

Grade	Ambient Temperature	GND	Vcc
Commercial	0°C to +70°C	0V	5.0V ± 10%
Industrial	-40°C to +85°C	0V	5.0V <u>+</u> 10%

2691 tbl 02

NOTES:

2691 tbl 00

- 1. This is the parameter TA.
- Industrial temperature: for specific speeds, packages and powers contact your sales office.

Absolute Maximum Ratings(1)

Symbol	Rating	Commercial & Industrial	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	V
TBIAS	Temperature Under Bias	-55 to +125	°C
Тѕтс	Storage Temperature	-55 to +125	°C
ЮИТ	DC Output Current	50	mA
			2691 tbl 01

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS
 may cause permanent damage to the device. This is a stress rating only
 and functional operation of the device at these or any other conditions
 above those indicated in the operational sections of the specification is not
 implied. Exposure to absolute maximum rating conditions for extended
 periods may affect reliability.
- 2. VTERM must not exceed Vcc+ 10% for more than 25% of the cycle time or 10ns maximum, and is limited to \leq 20mA for the period of VTERM \geq Vcc+ 10%.

Recommended DC Operating Conditions

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vcc	Supply Voltage	4.5	5.0	5.5	٧
GND	Ground	0	0	0	٧
VIH	Input High Voltage	2.2		6.0(2)	٧
VIL	Input Low Voltage	-0.5 ⁽¹⁾	_	0.8	٧

2691 tbl 03

NOTES:

- 1. V_{\parallel} (min.) = -1.5V for pulse width less than 10ns.
- 2. VTERM must not exceed Vcc + 10%.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range^(1,4,6) (Vcc = 5.0V ± 10%)

							7142	1X20 1X20 Only	7142	1X25 1X25 I Only	
Symbol	Parameter	Test Condition	Versi	on	Тур.	Max.	Тур.	Max.	Unit		
lcc	Dynamic Operating Current (Both Ports Active)	CEL and CER = VIL, Outputs Open f = fmax ⁽²⁾	COM'L	SA LA	110 110	250 200	110 110	220 170	mA		
	T = MAX**/	IND	SA LA								
ISB1	(Both Ports - TTL $f = f_{MAX}^{(2)}$	\overline{CEL} and $\overline{CER} = VIH$ $f = f_{MAX}^{(2)}$	COM'L	SA LA	30 30	65 45	30 30	65 45	mA		
Level Inputs)		IND	SA LA				_				
ISB2	(One Port - TTL Active Port Outputs Open,	COM'L	SA LA	65 65	165 125	65 65	150 115	mA			
	Level Inputs)	f=fMaX ⁽²⁾	IND	SA LA	_			_			
ISB3	Full Standby Current (Both Ports - CMOS Level Inputs)	CEL and CER ≥ Vcc - 0.2V,	COM'L	SA LA	1.0 0.2	15 5	1.0 0.2	15 5	mA		
	Civios Level inpuis)	S Level Inputs) $ \begin{array}{c} \text{Vin} \geq \text{Vcc} - 0.2 \text{V or} \\ \text{Vin} \leq 0.2 \text{V, f} = 0^{(3)} \end{array} $	IND	SA LA	_		_	_			
ISB4	(One Port - $\overline{CE}^*B^* \ge VCC - 0.2V^{(5)}$	CE"B" ≥ Vcc - 0.2V ⁽⁵⁾	COM'L	SA LA	60 60	155 115	60 60	145 105	mA		
	ČMOS Level Inputs)	V IN $\geq V$ CC - $0.2V$ or V IN $\leq 0.2V$ Active Port Outputs Open, $f = f$ MAX $^{(2)}$	IND	SA LA			_				

2691 tbl 04a

					7142	1X35 1X35 I Only	7142 Co	:1X55 :1X55 :m'l Ind	
Symbol	Param eter	Test Condition	Versi	on	Тур.	Max.	Тур.	Max.	Unit
lcc	Dynamic Operating Current (Both Ports Active)	CEL and CER = VIL, Outputs Open f = Max ⁽²⁾	COM'L	SA LA	80 80	165 120	55 55	155 110	mA
	IsB1 Standby Current	IND	SA LA	1 1		85 85	190 140		
ISB1	(Both Ports - TTL	f = fmax ⁽²⁾	COM'L	SA LA	25 25	65 45	20 20	65 35	mA
	Level Inputs)		IND	SA LA			20 20	65 45	
ISB2	Standby Current (One Port - TTL	CE"a" = Vil. and CE"b" = Viн(5) Active Port Outputs Open,	COM'L	SA LA	50 50	125 90	40 40	110 75	mA
	Level Inputs)	f=fmax ⁽²⁾	IND	SA LA	_		40 40	125 90	
ISB3	Full Standby Current (Both Ports -	CEL and CER ≥ Vcc - 0.2V,	COM'L	SA LA	1.0 0.2	15 4	1.0 0.2	15 4	mA
	CMOS Level Inputs) $V_{\text{IN}} \ge V_{\text{CC}} - 0.2V \text{ or } V_{\text{IN}} \le 0.2V, \text{ f} = 0^{(3)}$	$\forall N \ge VCC - 0.2V \text{ or } VN \le 0.2V, f = 0^{(3)}$	IND	SA LA			1.0 0.2	30 10	
ISB4	(One Port - CE"s" ≥ Vcc - 0.2V ⁽⁵⁾	COM'L	SA LA	45 45	110 85	40 40	100 70	mA	
	ČMOS Level Inputs)	$Vin \ge Vcc - 0.2V$ or $Vin \le 0.2V$ Active Port Outputs Open, $f = fimax^{(2)}$	IND	SA LA		_	40 40	110 85	

NOTES:

2691 tbl 04b

- 1. 'X' in part numbers indicates power rating (SA or LA).
- 2. At f = fmax, address and control lines (except Output Enable) are cycling at the maximum frequency read cycle of 1/tnc, and using "AC TEST CONDITIONS" of input levels of GND to 3V.
- 3. f = 0 means no address or control lines change. Applies only to inputs at CMOS level standby.
- 4. Vcc = 5V, Ta=+25°C for Typ and is not production tested. Vcc DC = 100mA (Typ)
- 5. Port "A" may be either left or right port. Port "B" is opposite from port "A".
- 6. Industrial temperature: for other speeds, packages and powers contact your sales office.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range (Vcc = 5.0V ± 10%)

			71321SA 71421SA		71321LA 71 4 21LA		
Symbol	Parameter	Test Conditions	Min.	Max.	Min.	Max.	Unit
lu	Input Leakage Current ⁽¹⁾	Vcc = 5.5V, Vin = 0V to Vcc	_	10	_	5	μΑ
[ILO]	Output Leakage Current ⁽¹⁾	CE = V _H , Vo∪т = 0V to Vcc, Vcc - 5.5V	_	10	_	5	μA
Vol	Output Low Voltage (I/Oo-I/O7)	loL = 4mA	_	0.4	_	0.4	٧
Vol	Open Drain Output Low Voltage (BUSY/INT)	IOL = 16mA	_	0.5	_	0.5	V
Vон	Output High Voltage	IOH = -4mA	2.4	-	2.4	_	V

NOTE:

2691 tbl 05

Data Retention Characteristics (LA Version Only)

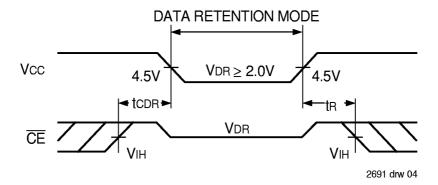
Symbol	Parameter	Test Condition	Min.	Typ. ⁽¹⁾	Max.	Unit	
VDR	Vcc for Data Retention			2.0		0	٧
ICCDR	Data Retention Current	Vcc = 2.0V, CE ≥ Vcc - 0.2V	COM'L	_	100	1500	μA
		V _{IN} ≥ V _{CC} - 0.2V or V _{IN} ≤ 0.2V	IND	_	100	4000	μA
tcdr ⁽³⁾	Chip Deselect to Data Retention Time			0	_	_	ns
tr(3)	Operation Recovery Time			trc ⁽²⁾		_	ns

NOTES:

2691 tbl 06

- 1. Vcc = 2V, TA = +25°C, and is not production tested.
- 2. tRC = Read Cycle Time
- 3. This parameter is guaranteed but not production tested.

Data Retention Waveform



^{1.} At Vcc ≤ 2.0V leakages are undefined.

AC Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	5 ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
Output Load	Figures 1,2 and 3

2691 tbl 07

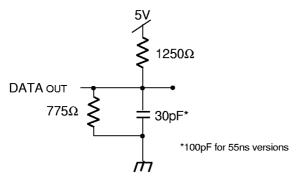


Figure 1. AC Output Test Load

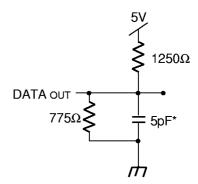


Figure 2. Output Test Load (for thz, tLz, twz, and tow)
* Including scope and jig.

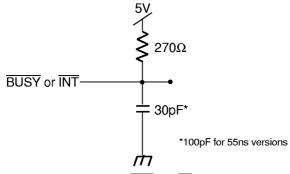


Figure 3. BUSY and INT AC Output Test Load

2691 drw 05

AC Electrical Characteristics Over the Operating Temperature Supply Voltage Range^(2,4)

		71321X20 71421X20 Com'l Only		71321X25 71421X25 Com'l Only		
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
READ CYCLE						
trc	Read Cycle Time	20	_	25	_	ns
taa	Address Access Time		20	_	25	ns
tace	Chip Enable Access Time		20	_	25	ns
tage	Output Enable Access Time	_	11	_	12	ns
toн	Output Hold from Address Change	3	_	3	_	ns
t .z	Output Low-Z Time ^(1,3)	0	_	0	_	ns
tHZ	Output High-Z Time ^(1,3)	_	10	_	10	ns
t₽U	Chip Enable to Power Up Time ⁽³⁾	0		0		ns
tPD	Chip Disable to Power Down Time ⁽³⁾	_	20	_	25	ns

2691 tbl 08a

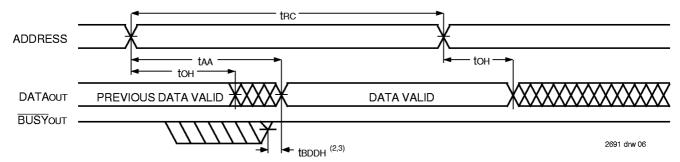
		71321X35 71421X35 Com'l Only		71321X55 71421X55 Com'l & Ind			
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit	
READ CYCLE	AD CYCLE						
trc	Read Cycle Time	35		55	_	ns	
taa	Address Access Time	_	35	_	55	ns	
tace	Chip Enable Access Time	_	35	_	55	ns	
tage	Output Enable Access Time	_	20	_	25	ns	
toн	Output Hold from Address Change	3	_	3	_	ns	
tı z	Output Low-Z Time ^(1,3)	0	_	5	_	ns	
tHZ	Output High-Z Time ^(1,3)	_	15	_	25	ns	
ten	Chip Enable to Power Up Time ⁽³⁾	0	_	0	_	ns	
tPD	Chip Disable to Power Down Time ⁽³⁾		35	_	50	ns	

NOTES:

- 1. Transition is measured ±500mV from Low or High-impedance voltage Output Test Load (Figure 2).
- 2. 'X' in part numbers indicates power rating (SA or LA).
- 3. This parameter is guaranteed by device characterization, but is not production tested.
- 4. Industrial temperature: for other speeds, packages and powers contact your sales office.

2691 tbl 08b

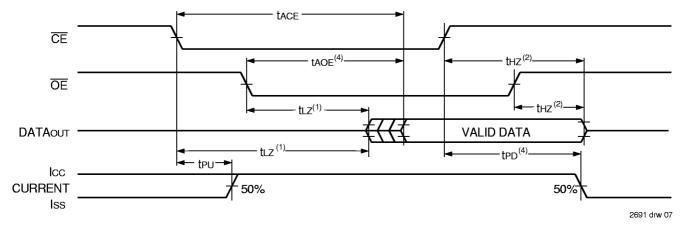
Timing Waveform of Read Cycle No. 1, Either Side(1)



NOTES:

- 1. $R\overline{W} = VIH$, $\overline{CE} = VIL$, and is $\overline{OE} = VIL$. Address is valid prior to the coincidental with \overline{CE} transition LOW.
- 2. tend delay is required only in the case where the opposite port is completing a write operation to the same address location. For simultaneous read operations BUSY has no relationship to valid output data.
- 3. Start of valid data depends on which timing becomes effective last tAOE, tACE, tAA, and tBDD.

Timing Waveform of Read Cycle No. 2, Either Side (3)



NOTES:

- 1. Timing depends on which signal is asserted last, \overline{OE} or \overline{CE} .
- 2. Timing depends on which signal is de-asserted first, $\overline{\text{OE}}$ or $\overline{\text{CE}}$.
- 3. $R\overline{W} = VIH$ and $\overline{OE} = VIL$, and the address is valid prior to or coincidental with \overline{CE} transition LOW.
- 4. Start of valid data depends on which timing becomes effective last tAOE, tACE, tAA, and tBDD.

AC Electrical Characteristics Over the Operating Temeprature and Supply Voltage Range^(4,5)

		71321X20 71421X20 Com'l Only		71321X25 71421X25 Com'l Only		
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
WRITE CYCLE	•					
twc	Write Cycle Time ⁽²⁾	20	_	25	_	ns
tew	Chip Enable to End-of-Write	15	_	20	_	ns
taw	Address Valid to End-of-Write	15	_	20	_	ns
tas	Address Set-up Time	0	_	0	_	ns
twp	Write Pulse Width ⁽³⁾	15	_	15	_	ns
twr	Write Recovery Time	0	_	0	_	ns
tow	Data Valid to End-of-Write	10	_	12	_	ns
tHZ	Output High-Z Time ⁽¹⁾	_	10	_	10	ns
to _H	Data Hold Time	0	_	0	_	ns
twz	Write Enable to Output in High-Z ¹⁾	_	10	_	10	ns
tow	Output Active from End-of-Write ⁽¹⁾	0	_	0		ns

2691 tbl 09a

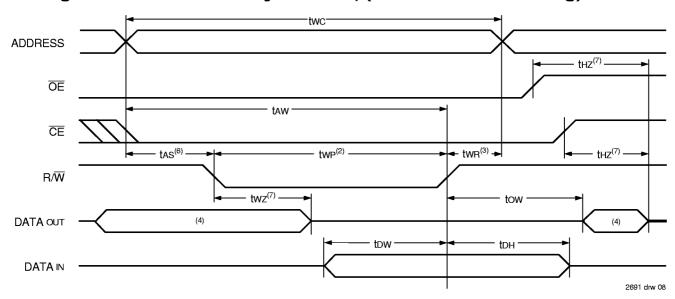
		7142	1X35 1X35 I Only	7142	71321X55 71421X55 Com'l & Ind	
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
WRITE CYCLE						
twc	Write Cycle Time ⁽²⁾	35	_	55	_	ns
tew	Chip Enable to End-of-Write	30	_	40	_	ns
taw	Address Valid to End-of-Write	30	_	40	_	ns
tas	Address Set-up Time	0	_	0	_	ns
twp	Write Pulse Width ⁽³⁾	25	_	30	_	ns
twr	Write Recovery Time	0	_	0	_	ns
tow	Data Valid to End-of-Write	15	_	20	_	ns
tHZ	Output High-Z Time ⁽¹⁾	_	15	_	25	ns
toн	Data Hold Time	0		0	_	ns
twz	Write Enable to Output in High-Z ⁽¹⁾	_	15	_	30	ns
tow	Output Active from End-of-Write ⁽¹⁾	0	_	0	_	ns

NOTES:

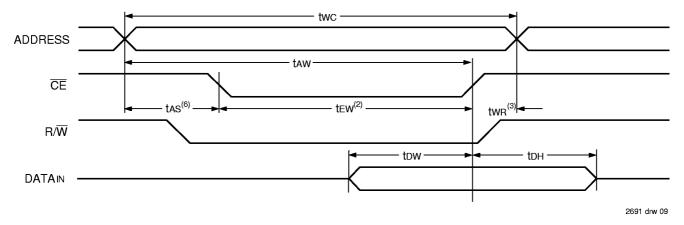
2691 tbl 09b

- 1. Transition is measured ±500mV from Low or High-impedance voltage with Output Test Load (Figure 2). This parameter is guaranteed by device characterization but is not production tested.
- 2. For Master/Slave combination, two = tbaa + twp, since $R\overline{W}$ = V_{IL} must occur after tbaa .
- 3. If \overline{OE} is LOW during a R/W controlled write cycle, the write pulse width must be the larger of two or (twz + tow) to allow the I/O drivers to turn off data to be placed on the bus for the required tow. If \overline{OE} is HIGH during a R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.
- 4. 'X' in part numbers indicates power rating (SA or LA).
- 5. Industrial temperature: for other speeds, packages and powers contact your sales office.

Timing Waveform of Write Cycle No. 1, (R/W Controlled Timing)(1,5,8)



Timing Waveform of Write Cycle No. 2, (CE Controlled Timing)(1,5)



NOTES:

- 1. $R\overline{W}$ or \overline{CE} must be HIGH during all address transitions.
- 2. A write occurs during the overlap (tew or twp) of \overline{CE} = Vil and R/W= Vil.
- 3. twn is measured from the earlier of \overline{CE} or R/\overline{W} going HIGH to the end of the write cycle.
- 4. During this period, the I/O pins are in the output state and input signals must not be applied.
- 5. If the CE LOW transition occurs simultaneously with or after the R/W LOW transition, the outputs remain in the High-impedance state.
- 6. Timing depends on which enable signal (\overline{CE} or $R\overline{W}$) is asserted last.
- 7. This parameter is determined to be device characterization, but is not production tested. Transition is measured ±500mV from steady state with the Output Test Load (Figure 2).
- 8. If \overline{OE} is LOW during a R/W controlled write cycle, the write pulse width must be the larger of twp or (twz + tow) to allow the I/O drivers to turn off data to be placed on the bus for the required tow. If \overline{OE} is HIGH during a R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range^(6,7)

		7142	21X20 21X20 Il Only	7142	21X25 21X25 I Only	
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
BUSY TIMING	(For MASTER 71321)					
t BAA	BUSY Access Time from Address	_	20	_	20	ns
t BDA	BUSY Disable Time from Address	_	20	_	20	ns
t BAC	BUSY Access Time from Chip Enable	_	20	_	20	ns
t BDC	BUSY Disable Time from Chip Enable	_	20	_	20	ns
twн	Write Hold After BUSY ⁽⁵⁾	12	_	15	_	ns
twoo	Write Pulse to Data Delay ⁽¹⁾	_	50	_	50	ns
todo	Write Data Valid to Read Data Delay ⁽¹⁾	_	35	_	35	ns
taps	Arbitration Priority Set-up Time ⁽²⁾	5	_	5	_	ns
tBDD	BUSY Disable to Valid Data ⁽³⁾	_	25	_	35	ns
BUSY INPUT 1	TIMING (For SLAVE 71421)					
twB	Write to BUSY Input ⁽⁴⁾	0	_	0	_	ns
twн	Write Hold After BUSY ⁽⁵⁾	12	_	15	_	ns
twoo	Write Pulse to Data Delay ⁽¹⁾	-	40	_	50	ns
todo	Write Data Valid to Read Data Delay ⁽¹⁾	_	30	_	35	ns

2691 tbl 10a

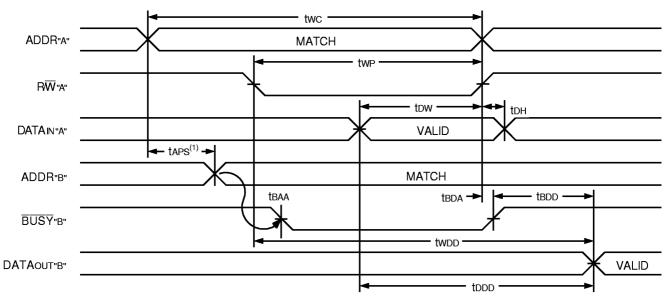
		7142	1X35 1X35 I Only	7132 7142 Co &		
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
BUSY TIMING	(For MASTER 71321)					
t BAA	BUSY Access Time from Address	_	20	-	30	ns
t BDA	BUSY Disable Time from Address		20	-	30	ns
t BAC	BUSY Access Time from Chip Enable	_	20	_	30	ns
t BDC	BUSY Disable Time from Chip Enable	_	20	_	30	ns
twн	Write Hold After BUSY ⁽⁵⁾	20	_	20	_	ns
twoo	Write Pulse to Data Delay ⁽¹⁾	_	60	_	80	ns
todo	Write Data Valid to Read Data Delay ⁽¹⁾	_	35	_	55	ns
taps	Arbitration Priority Set-up Time ⁽²⁾	5	1	5	1	ns
1BDD	BUSY Disable to Valid Data ⁽³⁾	_	35	_	50	ns
BUSY INPUT 1	IMING (For SLAVE 71421)					
twB	Write to BUSY Input ⁽⁴⁾	0	_	0	_	ns
twн	Write Hold After BUSY ⁽⁵⁾	20		20	1	ns
twoo	Write Pulse to Data Delay ⁽¹⁾		60	-	80	ns
todo	Write Data Valid to Read Data Delay ⁽¹⁾	_	35	_	55	ns

NOTES

2691 tbl 10b

- 1. Port-to-port delay through RAM cells from the writing port to the reading port, refer to "Timing Waveform of Write with Port-to-Port Read and BUSY."
- 2. To ensure that the earlier of the two ports wins.
- 3. tbdd is a calculated parameter and is the greater of 0, twdd twp (actual) or tddd tdw (actual).
- 4. To ensure that a write cycle is inhibited on port "B" during contention on port "A".
- 5. To ensure that a write cycle is completed on port "B" after contention on port "A".
- 6. 'X' in part numbers indicates power rating (SA or LA).
- 7. Industrial temperature: for other speeds, packages and powers contact your sales office.

Timing Waveform of Write with Port-to-Port Read and BUSY (2,3,4)

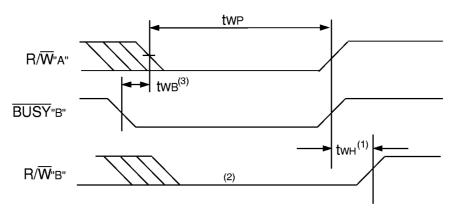


NOTES:

2691 drw 10

- 1. To ensure that the earlier of the two ports wins. taps is ignored for Slave (71421).
- 2. $\overline{CEL} = \overline{CER} = VIL$
- 3. $\overline{OE} = V_{IL}$ for the reading port.
- 4. All timing is the same for the left and right ports. Port "A" may be either the left or right port. Port "B" is opposite from port "A".

Timing Waveform of Write with BUSY (4)

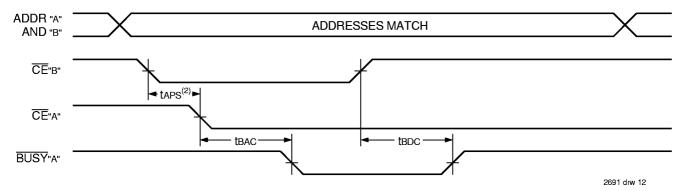


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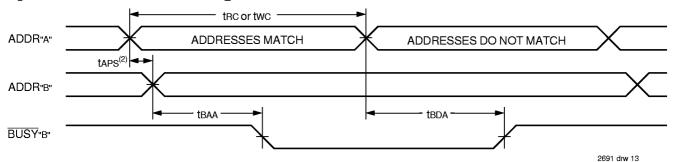
2691 drw 11

- 1. twn must be met for both BUSY input (71421, slave) or output (71321, Master).
- 2. BUSY is asserted on port "B" blocking RWB, until BUSYB goes HIGH.
- 3. twB is only for the slave version (71421).
- 4. All timing is the same for the left and right ports. Port "A" may be either the left or right port. Port "B" is opposite from port "A".

Timing Waveform of BUSY Arbitration Controlled by CE Timing⁽¹⁾



Timing Waveform of BUSY Arbritration Controlled by Address Match Timing⁽¹⁾



NOTES:

- 1. All timing is the same for left and right ports. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
- 2. If taps is not satisified, the BUSY will be asserted on one side or the other, but there is no guarantee on which side BUSY will be asserted (71321 only).

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range^(1,2)

		7142	1X20 1X20 Only	7132 7142 Com'						
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit				
INTERRUPT TIMING										
tas	Address Set-up Time	0	_	0	_	ns				
twr	Write Recovery Time	0	_	0	_	ns				
tins	Interrupt Set Time	_	20	_	25	ns				
tinr	Interrupt Reset Time	_	20	_	25	ns				

NOTES

- 1. 'X' in part numbers indicates power rating (SA or LA).
- 2. Industrial temperature: for other speeds, packages and powers contact your sales office.

2691 thl 11a

AC Electrical Characteristics Over the Operating Temperature Supply Voltage Range (1,2)

		7142	1X35 1X35 I Only	7132 7142 Co &							
Symbol	Parameter	Max.	Min.	Max.	Unit						
INTERRUPT T	INTERRUPT TIMING										
tas	Address Set-up Time	0	_	0	_	ns					
twr	Write Recovery Time	0	_	0	_	ns					
tins	Interrupt Set Time	_	25	_	45	ns					
tinr	Interrupt Reset Time	_	25	_	45	ns					

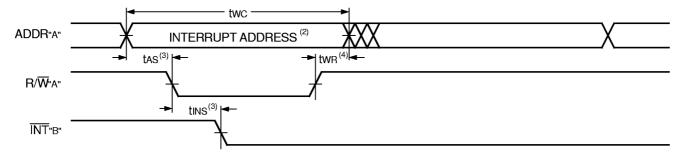
NOTES:

2691 tbl 11b

- 1. 'X' in part numbers indicates power rating (SA or LA).
- 2. Industrial temperature: for other speeds, packages and powers contact your sales office.

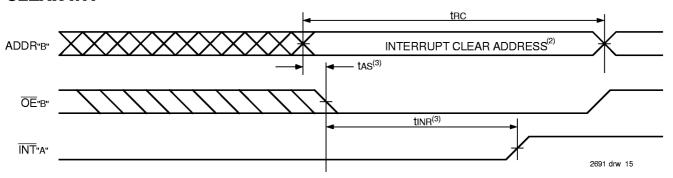
Timing Waveform of Interrupt Mode⁽¹⁾

SET INT



2691 drw 14

CLEAR INT



NOTES:

- 1. All timing is the same for left and right ports. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
- 2. See Interrupt Truth Table.
- 3. Timing depends on which enable signal $(\overline{CE} \text{ or } R\overline{W})$ is asserted last. 4. Timing depends on which enable signal $(\overline{CE} \text{ or } R\overline{W})$ is de-asserted first.

2691 tbl 13

Truth Tables

Truth Table I. Non-Contention Read/Write Control⁽⁴⁾

	Left or	Right Port ⁽¹⁾	r						
R/W	Œ	Œ	D 0-7	Function					
Х	Н	Χ	Z	Port Disabled and in Power-Down Mode, ISB2 or ISB4					
Х	Н	Χ	Z	Er = CEL = Vih, Power-Down Mode, ISB1 or ISB3					
L	L	Х	DATAIN	Data on Port Written Into Memory ⁽²⁾					
Н	L	L	DATAout	Data in Memory Output on Port ⁽³⁾					
Н	L	Н	Z	High Impedance Outputs					

NOTES: 2691 tbl 12

- 1. $A_{0L} A_{10L} \neq A_{0R} A_{10R}$.
- 2. If \overline{BUSY} = L, data is not written.
- 3. If BUSY = L, data may not be valid, see twop and topo timing.
- 4. 'H' = VIH, 'L' = VIL, 'X' = DON'T CARE, 'Z' = HIGH IMPEDANCE

Truth Table II. Interrupt Flag^(1,4)

		Left Port								
R/WL	CEL	ŌĒL	A10L-A0L	ĪNTL	R/W̄R	CER	ŌĒR	A10R-A0R	ĪNTR	Function
L	L	Х	7FF	Х	Х	Х	Х	Х	L ⁽²⁾	Set Right INTR Flag
Х	Х	Х	Х	Х	Х	L	L	7FF	H ⁽³⁾	Reset Right INTR Flag
Х	Х	Х	Х	L ⁽³⁾	L	L	Х	7FE	Х	Set Left INTL Flag
Х	٦	L	7FE	H ⁽²⁾	Х	Х	Х	Х	Х	Reset Left INTL Flag

NOTES:

- 1. Assumes $\overline{\text{BUSYL}} = \overline{\text{BUSYR}} = \text{V}_{\text{IH}}$
- 2. If BUSYL = VIL, then No Change.
- 3. If BUSYR = VIL, then No Change.
- 4. 'H' = HIGH, 'L' = LOW, 'X' = DON'T CARE

Truth Table III — Address BUSY Arbitration

	In	puts	Out	puts	
CEL	CER	A0L-A10L A0R-A10R	BUSYL(1)	BUSYR ⁽¹⁾	Function
Х	Х	NO MATCH	Н	Η	Normal
Н	Х	MATCH	Н	Н	Normal
Х	Н	MATCH	Н	Н	Normal
L	L	MATCH	(2)	(2)	Write Inhibit ⁽³⁾

NOTES: 2691 tbl 14

- 1. Pins BUSYL and BUSYR are both outputs for 71321 (Master). Both are inputs for 71421 (Slave). BUSYx outputs on the 71321 are open drain, not push-pull outputs.

 On slaves the BUSYx input internally inhibits writes.
- 2. 'L' if the inputs to the opposite port were stable prior to the address and enable inputs of this port. 'H' if the inputs to the opposite port became stable after the address and enable inputs of this port. If tAPS is not met, either BUSYL or BUSYR = LOW will result. BUSYL and BUSYR outputs can not be LOW simultaneously.
- 3. Writes to the left port are internally ignored when BUSYL outputs are driving LOW regardless of actual logic level on the pin. Writes to the right port are internally ignored when BUSYR outputs are driving LOW regardless of actual logic level on the pin.

Functional Description

The IDT71321/IDT71421 provides two ports with separate control, address and I/O pins that permit independent access for reads or writes to any location in memory. The IDT71321/IDT71421 has an automatic power down feature controlled by $\overline{\text{CE}}$. The $\overline{\text{CE}}$ controls on-chip power down circuitry that permits the respective port to go into a standby mode when not selected ($\overline{\text{CE}} = \text{V}_{\text{IH}}$). When a port is enabled, access to the entire memory array is permitted.

Interrupts

If the user chooses the interrupt function, a memory location (mail box or message center) is assigned to each port. The left port interrupt flag ($\overline{\text{INTL}}$) is asserted when the right port writes to memory location 7FE (HEX), where a write is defined as the $\overline{\text{CE}}_R = R/\overline{W}_R = V_{\text{IL}}$, per Truth Table II. The left port clears the interrupt by accessing address location 7FE when $\overline{\text{CE}}_L = \overline{\text{OE}}_L = V_{\text{IL}}$, R/W is a "don't care". Likewise, the right port interrupt flag ($\overline{\text{INTR}}$) is asserted when the left port writes to memory location 7FF (HEX) and to clear the interrupt flag ($\overline{\text{INTR}}$), the right port must access the memory location 7FF. The message (8 bits) at 7FE or 7FF is user-defined, since it is an addressable SRAM location. If the interrupt function is not used, address locations 7FE and 7FF are not used as mail boxes, but as part of the random access memory. Refer to Truth Table II for the interrupt operation.

Busy Logic

Busy Logic provides a hardware indication that both ports of the RAM have accessed the same location at the same time. It also allows one of the two accesses to proceed and signals the other side that the RAM is "Busy". The $\overline{\text{BUSY}}$ pin can then be used to stall the access until the operation on the other side is completed. If a write operation has been attempted from the side that receives a busy indication, the write signal is gated internally to prevent the write from proceeding.

The use of \overline{BUSY} Logic is not required or desirable for all applications. In some cases it may be useful to logically OR the \overline{BUSY} outputs together and use any \overline{BUSY} indication as an interrupt source to flag the event of an illegal or illogical operation. In slave mode the \overline{BUSY} pin operates solely as a write inhibit input pin. Normal operation can be programmed by tying the \overline{BUSY} pins HIGH. If desired, unintended write operations can be prevented to a port by tying the \overline{BUSY} pin for that port LOW.

The BUSY outputs on the IDT71321 (Master) are open drain type outputs and require open drain resistors to operate. If these SRAMs are

being expanded in depth, then the BUSY indication for the resulting array does not require the use of an external AND gate.

Width Expansion with Busy Logic Master/Slave Arrays

When expanding an SRAM array in width while using \overline{BUSY} logic, one master part is used to decide which side of the SRAM array will receive a \overline{BUSY} indication, and to output that indication. Any number of slaves to be addressed in the same address range as the master, use the \overline{BUSY} signal as a write inhibit signal. Thus on the IDT71321/IDT71421 SRAMs the \overline{BUSY} pin is an output if the part is Master (IDT7132), and the \overline{BUSY} pin is an input if the part is a Slave (IDT7142) as shown in Figure 3.

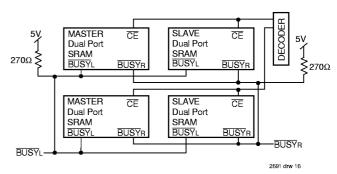
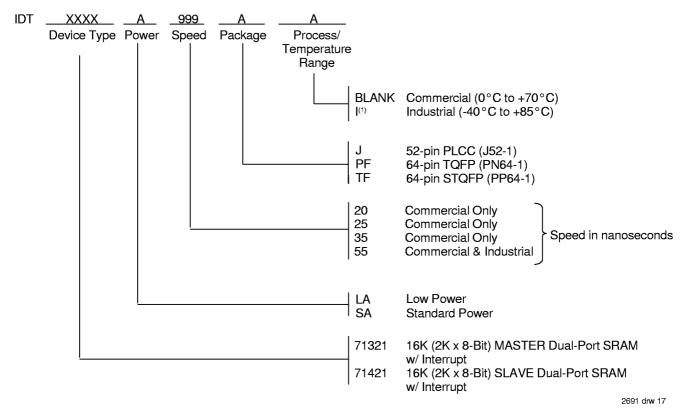


Figure 3. Busy and chip enable routing for both width and depth expansion with IDT71321 (Master) and (Slave) IDT71421 SRAMs.

If two or more master parts were used when expanding in width, a split decision could result with one master indicating \overline{BUSY} on one side of the array and another master indicating \overline{BUSY} on one other side of the array. This would inhibit the write operations from one port for part of a word and inhibit the write operations from the other port for the other part of the word.

The \overline{BUSY} arbitration, on a Master, is based on the chip enable and address signals only. It ignores whether an access is a read or write. In a master/slave array, both address and chip enable must be valid long enough for a \overline{BUSY} flag to be output from the master before the actual write pulse can be initiated with either the R/\overline{W} signal or the byte enables. Failure to observe this timing can result in a glitched internal write inhibit signal and corrupted data in the slave.

Ordering Information



NOTE:

Industrial temperature range is available in selected PLCC packages in standard power.
 For other speeds, packages and powers contact your sales office.

Datasheet Document History

3/24/99: Initiated datasheet document history

Converted to new format

Cosmetic typographical corrections

Pages 2 and 3 Added additional notes to pin configurations



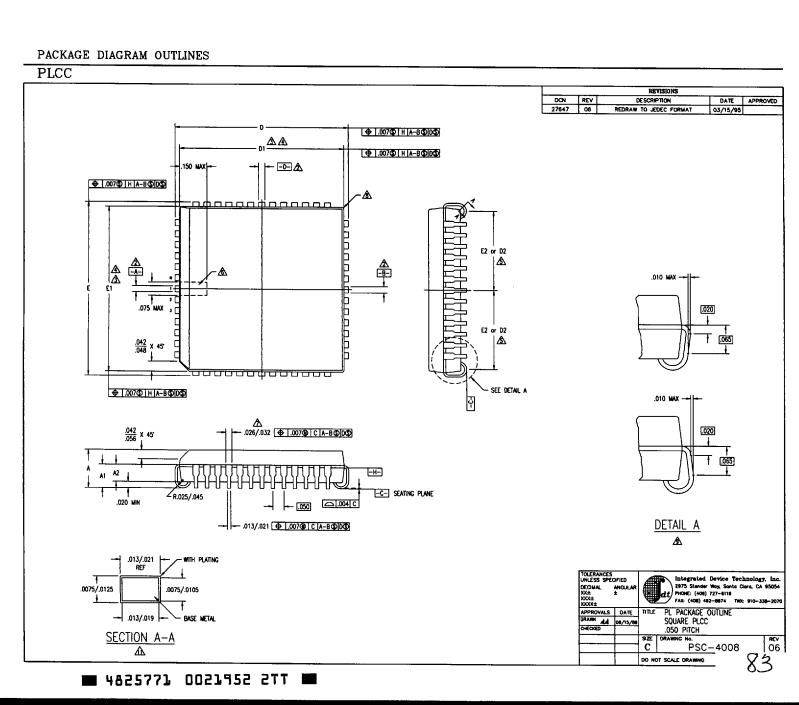
CORPORATE HEADQUARTERS

2975 Stender Way Santa Clara, CA 95054 for SALES:

800-345-7015 or 408-727-6116 fax: 408-492-8674 www.idt.com

for Tech Support: 831-754-4613 DualPortHelp@idt.com

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PACKAGE DIAGRAM OUTLINES

PLCC (Continued)

	REVISIONS										
DCN	REV	DESCRIPTION	DATE	APPROVED							
27647	06	REDRAW TO JEDEC FORMAT	03/15/95								

	DWG #		J28-	1	DWG	1	J44-	1	DWG	1	J52-	1	DWG	#	J68-	1	DWG	#	J84-	1									
Ş	JEDE	C VARIAT	ION	N	JEDEC VARIATION		N JEDEC		JEDEC VARIATI		JEDEC VARIATION		JEDEC VARIATION		JEDEC VARIATION		JEDEC VARIATION		JEDEC VARIAT		N	JEDE	JEDEC VARIATION		N	JEDE	C VARIAT	ION	
9		AB] 🖁		AC] P		AD		🖁		AE		P		AF		ļĝ									
Ľ	MIN	NOM	MAX	E	MIN	NOM	MAX	É	MIN	NOM	MAX	Ė	MIN	NOM	MAX	È	MIN	NOM	MAX	Ė									
A	.165	.172	.180		.165	.172	.180		.165	.172	.180		.165	.172	.180		.165	.172	.180										
A1	.095	.105	.115		.095	.105	.115		.095	.105	.115		.095	.105	.115		.095	.105	.115	_									
A2	.062	_	.083		.062	-	.083		.062	T -	.083		.062	-	.083	М	.059	-	.080	_									
D	.485	.490	.495		.685	.690	.695		.785	.790	.795		.985	.990	.995		1.185	1,190	1.195										
D1	.450	.453	.456	3,4	.650	.653	.656	3,4	.750	.753	.756	3,4	.950	.953	.956	3.4	1,150	1.154	1,156	3.4									
D2	.195	.205	.215	5	.295	.305	.315	5	.345	.355	.365	5	.445	.455	.465	5	.545	.555	.565	5									
Ε	.485	.490	.495		.685	.690	.695		.785	.790	.795		.985	.990	.995		1.185	1,190	1,195	- <u>-</u>									
E١	.450	.453	.456	3,4	.650	.653	656	3,4	.750	.753	.756	3,4	.950	953	.956	3,4	1,150	1.154	1.156	3,4									
E2	.191	.205	.219	5	.291	.305	.319	5	.341	.355	.369	5	.441	.455	.469	5	.541	.555	.569	5									
N		28				44			1	52				68				84		Ť									

NOTES:

1 ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5M-1982

DATUMS A-B AND -D- TO BE DETERMINED AT DATUM PLANE -H-

⚠ DIMENSIONS D1 AND E1 ARE TO BE DETERMINED AT DATUM PLANE —H—

⚠ DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS .010 PER SIDE. D1 AND E1 ARE BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH

△ DIMENSIONS D2 AND E2 ARE TO BE DETERMINED AT SEATING PLANE —C—CONTACT POINT

DETAIL OF PIN 1 IDENTIFIER IS OPTIONAL BUT MUST BE LOCATED WITHIN THE ZONE INDICATED

LEAD WIDTH DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION IS .007 TOTAL MAXIMUM PER LEAD

A EXACT SHAPE OF EACH CORNER IS OPTIONAL

10 ALL DIMENSIONS ARE IN INCHES

 Φ

THIS OUTLINE CONFORMS TO JEDEC PUBLICATION 95 REGISTRATION MS-018, VARIATION AB, AC, AD, AE & AF. EXCEPTIONS: JEDEC MAXIMUM BASE METAL LEAD WIDTH IS .018

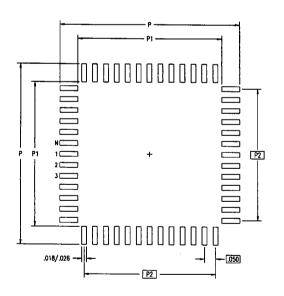
TOLERANCES UNLESS SPEI DECIMAL XX± XXX± XXXX±			Integrated Device Technology, Inc 2975 Stender Woy, Sento Gere, CA 9505- PAONE: (408) 482-8674 TWX: 910-338-20;					
APPROVALS	DATE	TITLE	PL PACKAGE OUTLI	NE				
DRAWN ALA	08/15/86	1	SQUARE PLCC					
CHECKED		1	.050 PITCH					
		SIZE	DRAWING No.		REV			
		С	PSC-40	800	06			
		DO NO	T SCALE DRAWING	01	1			
				0,	٦			

PACKAGE DIAGRAM OUTLINES

PLCC (Continued)

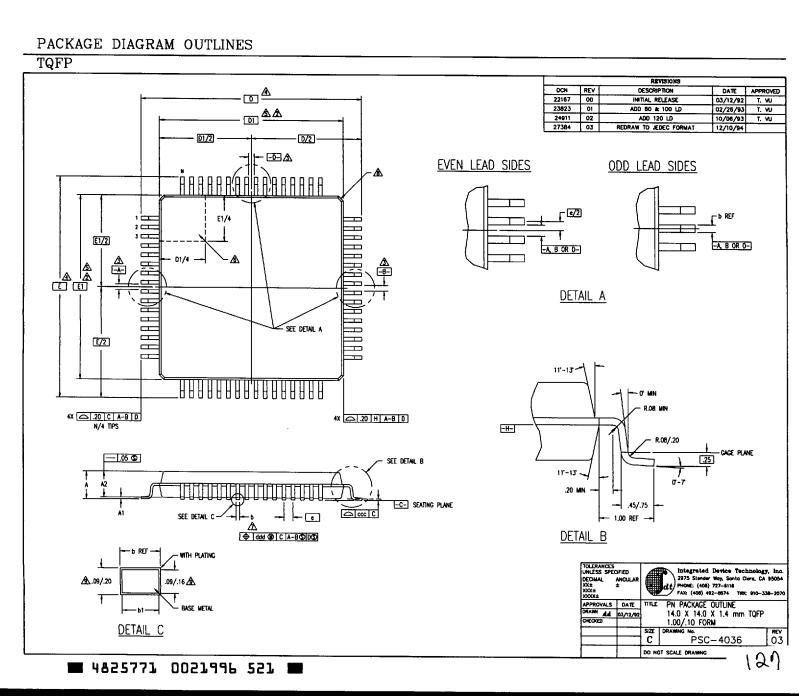
		REVISIONS		-
DCN	Æ	DESCRIPTION	DATE	APPROVED
27647	8	REDRAW TO JEDEC FORMAT	03/15/95	

LAND PATTERN DIMENSIONS



	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX
P	.520	.528	.720	.728	.820	.828	1.020	1.028	1.220	1.228
P1	.354	.362	.554	.562	.654	.662	.854	.862	1.054	1.062
P2	.300	BSC	.500	BSC	.600	BSC	.800	BSC	1.000	BSC
N	2	8	44			52	6	8	8	4

TOLERANCES UNLESS SPE DECIMAL XX± XXX± XXXX± XXXX±			Integrated Device Technolog 2975 Stender Woy, Sonto Clora, CA PHONE: (408) 727-8116 FAX: (408) 482-8674 TWX: 910-3	95054		
APPROVALS	DATE	TITLE PL PACKAGE OUTLINE				
DRAWN ALL	08/15/89	SQUARE PLCC				
CHECKED		ŀ	.050 PITCH			
		SZE	DRAWING No.	REV		
		С	PSC-4008	06		
				*		



PACKAGE DIAGRAM OUTLINES

TQFP (Continued)

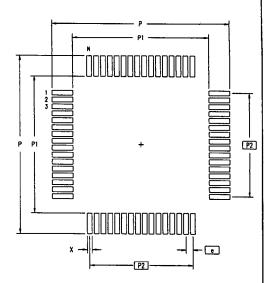
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Ş	JEDEC VARIATION				DEC VARIATION		JEDEC VARIATION			N	JEDE	C VARIAT	ION	N	JEDE	C VARIAT	ION				
B		BP		P	BQ		BQ		BQ			BR		1 9 1		BS		ğ			
,	MIN	NOM	MAX	E	MIN	NOM	MAX	Ē	MIN	NOM	MAX] É	MIN	NOM	MAX	Ė					
A	-		1.60		_	-	1.60		-	- ⁻	1.60			-	1.60						
A1	.05	.10	.15		.05	.10	.15		.05	.10	.15	П	.05	.10	.15						
A2	1.35	1.40	1.45		1.35	1.40	1.45		1.35	1.40	1.45		1.35	1.40	1.45						
٥		6.00 BS	C	4	16.00 BSC		4		16.00 BSC 4		4	16.00 BSC		4							
01	1	14.00 BS	С	5,2	1	14.00 BSC		5,2		14.00 BS	SC 5,2		14.00 BSC		5,2						
E	1	16.00 BS	C	4	1	16.00 BSC		4		16.00 BS	c	4		6.00 BS	C	4					
E١	.1	4.00 BS	С	5,2	1	14.00 BSC		5,2		14.00 BS	С	5,2	14.00 BSC		5.2						
N		64				80				100		П		120							
e		.80 BSC				.65 BSC				.50 BSC				.40 BSC							
Ь	.30	.37	.45	7	.22	.32	.38	7	.17	.22	.27	7	.13	.18	.23	7					
ы	.30	.35	.40		.22	.30	.33		.17	.20	.23		.13	.16	.19	1					
ccc	-	-	.10		-	_	.10		-	i -	.08	\Box	_	 -	.08						
ppp	-	_	.20		-	-	.13		-	 	.08		-	-	.07	1-					

NOTES:

- 1 ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5M-1982
- TOP PACKAGE MAY BE SMALLER THAN BOTTOM PACKAGE BY .15 mm
- ⚠ DATUMS A-B AND -D- TO BE DETERMINED AT DATUM PLANE -H-
- Δ DIMENSIONS D AND ε ARE TO BE DETERMINED AT SEATING PLANE -C-
- DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS .25 mm PER SIDE. D1 AND E1 ARE MAXIMUM BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH
- DETAILS OF PIN 1 IDENTIFIER IS OPTIONAL BUT MUST BE LOCATED WITHIN THE ZONE INDICATED
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION IS .08 mm in excess of the 6 dimension at maximum material condition. Dambar cannot be located on the lower radius or the foot.
- A EXACT SHAPE OF EACH CORNER IS OPTIONAL
- THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .10 AND .25 mm FROM THE LEAD TIP
- 10 ALL DIMENSIONS ARE IN MILLIMETERS
- 11 This outline conforms to jedec publication 95 registration MO-136, variation 8P, 8Q, 8R & 8S

	REVISIONS							
DCN	REV	DESCRIPTION	DATE	APPROVED				
22167	00	INITIAL RELEASE	03/12/92	T. VU				
23823	01	ADD 80 & 100 LD	02/26/93	T. VU				
24911	02	ADD 120 LD	10/06/93	T. VU				
27384	03	REDRAW TO JEDEC FORMAT	11/18/94					

LAND PATTERN DIMENSIONS

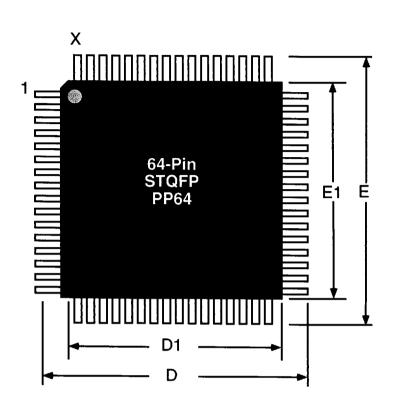


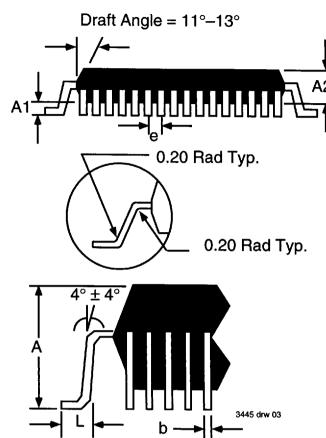
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P1	13.80	14.00	13.80	14.00	13.80	14.00	13.80	14.00
P2	12.00	BSC	12.35 BSC		12.00 BSC		11.60 BSC	
Χ	.40	.60	.30	.50	.30	40	.20	.30
e	.80 (.80 BSC .		.65 BSC		3SC	.40 (SSC SSC
N	64		80		1	00	1	20

TOLERANCES UNLESS SPE DECIMAL XX± XXX± XXXX±	CIRED ANGULAR ±	Integrated Device Technology, Inc. 2975 Stender Way, Sonte Clere, CA 95054 PHORE: (408) 927-6116 FAX: (408) 492-8874 TWX: 910-338-2070					
APPROVALS	DATE	TITLE	PN PACKAGE OUTLINE				
DRAWN ALA	03/12/92		14.0 X 14.0 X 1.4 mm TQFP				
CHECKED	· · · ·		1.00/.10 FORM				
		SIZE	DRAWING No.	REV			
		С	PSC-4036	03			
		DO NO	OT SCALE DRAWING	CX_			
			la	K			

■ 4825771 0021997 468 **■**

PACKAGE DIMENSIONS





DIMENSIONS

64-PIN STQFP WITH 10MM BODY

Dimension		5
DImension	Tolerance	Dimension
Letter	(mm)	(mm)
A	Max.	1.60
A1	<u>+</u> .05	0.10
A2	<u>+</u> .05	1.45
D	<u>+</u> .10	12.00
D1	<u>+</u> .10	10.00
E	<u>+</u> .10	12.00
E1	<u>+</u> .10	10.00
L	<u>+</u> 15	0.60
е	Basic	0.50
b	.05	0.22